



# Polarized electron source update

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# Laser System

- Slow progress at SLAC due to limited resources (both manpower and M&S)
- Plan is still to complete laser system and generate a polarized electron beam
- Intention is to draw resources from other laser groups at SLAC
- Investment in new pump laser still optional
- Meeting at Jlab on 04/20 to discuss integration of laser system and gun developed by Matt Poelker at Jlab



# Laser System SBIR with KM Labs

- Expecting completion of the project in ~ 4 months.
- Also trouble with pump lasers for Regen Amplifier
- Reduced scope of the project:
  - **Max repetition rate 1.5 MHz instead of 3 MHz**
- Lessons learned from project:
  - **Use 2x50W MOPA doubled Nd lasers or fiber-based green lasers to get ~ 100W of pump power**
  - **These option became available only recently**



# DC Gun R&D at Jlab

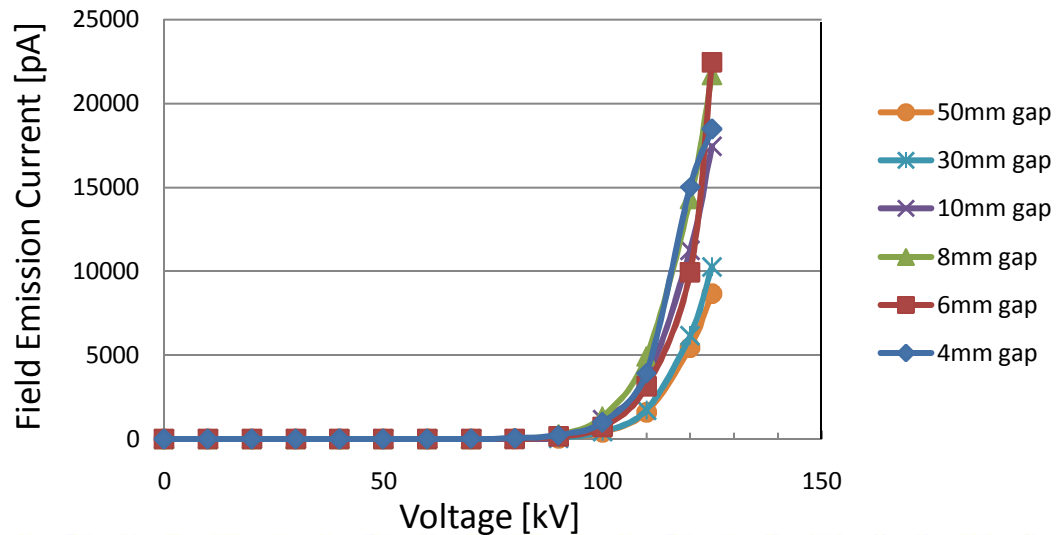
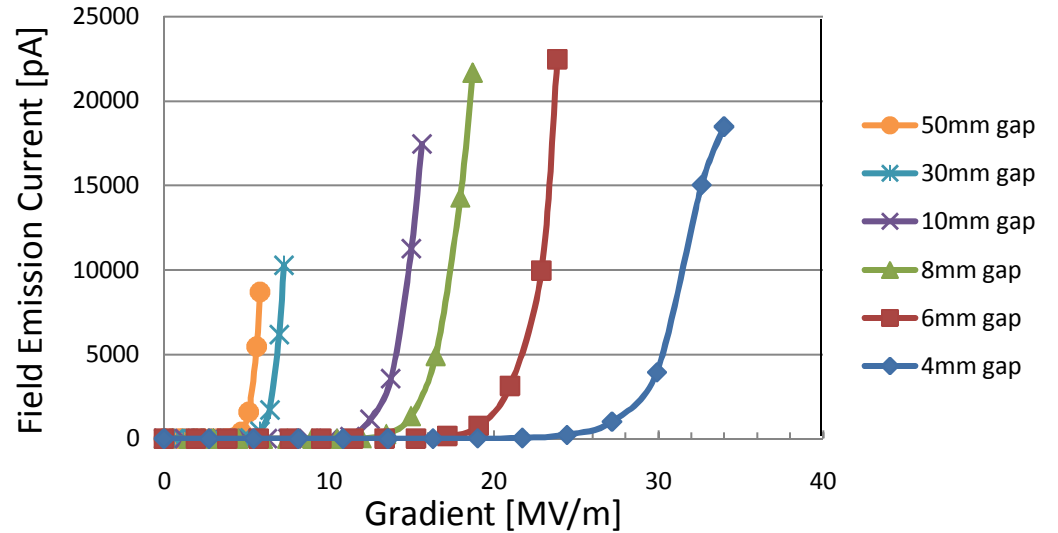
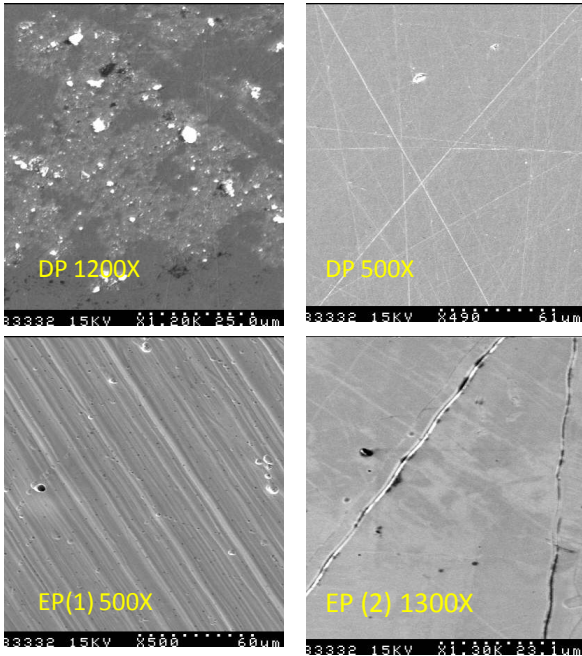
- Most important issue  
→ Reduce field emission from electrodes
- Tests of a variety of materials and polishing techniques<sup>[1]</sup>
  - **Stainless Steel**
    - Diamond paste polishing
    - Electro-polishing
  - **Single Crystal Niobium**
    - Buffer Chemical Polish
    - Diamond Paste Polish

<sup>[1]</sup> Work of Ken Surles-Law, Jefferson Lab



# Electro-polished Steel

- Results similar to diamond-paste polishing: limiting gradient 5MV/m
- Considerable time saving
- Perhaps better results if we start with smoother surface





# Single Crystal Niobium

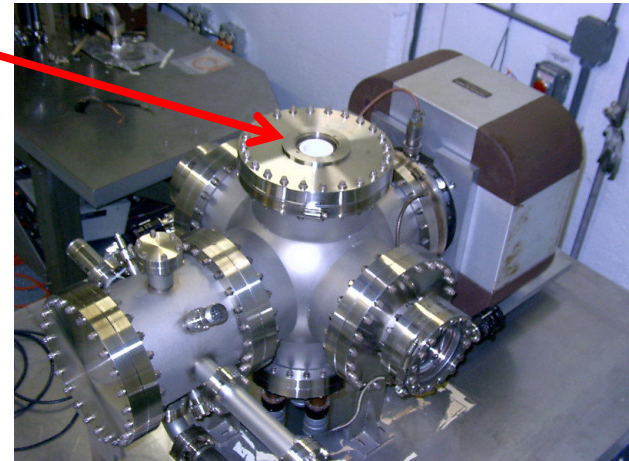
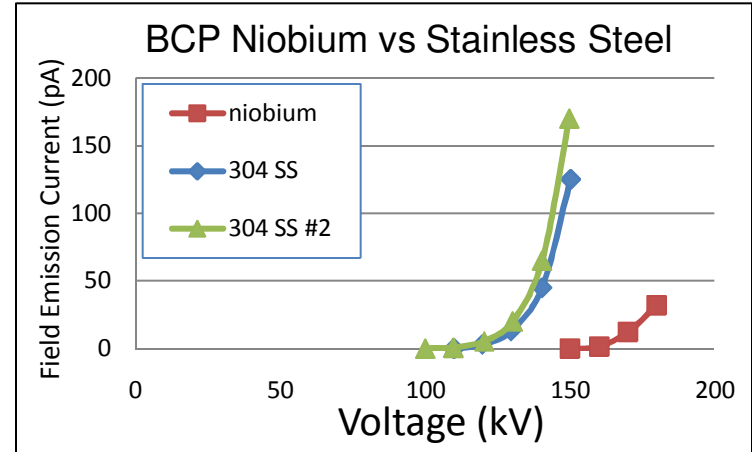
- Capable of operation at higher voltage and gradient
- Buffer chemical polish (BCP) much easier than diamond-paste-polish



Conventional geometry: cathode electrode mounted on metal support structure



Replace conventional ceramic insulator with "Inverted" insulator: no SF6 and no HV breakdown outside chamber





## High Temperature Bake to reduce outgassing rate



- As much “thin-wall” material as possible
- 316LN (L= low carbon, N= nitrogen added for hard knife edges)
- Manufactured and electropolished by NorCal
- 400C bakeout for 9 days, under vacuum
- Pumped by oil-free turbo, then added ion pump, while monitoring “effluent” with RGA
- At 9<sup>th</sup> day, vacuum still improving by ~15% per 24 hours
- RGA shows H<sub>2</sub>, methane, CO and HCl (from electropolishing)
- Rate of Rise method, with spinning rotor gauge, outgassing rate  $10^{-13}$ TL/scm<sup>2</sup>, one order of magnitude improvement
- Vented and remeasured good rate, on test chamber
- Now working to de-gas internal components...



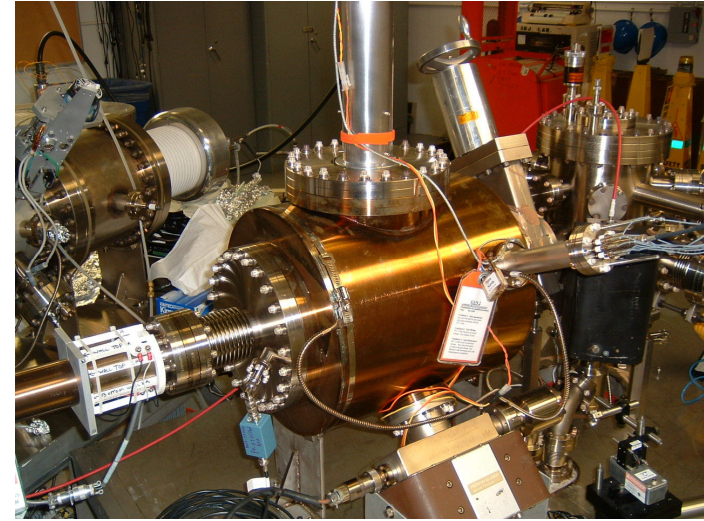
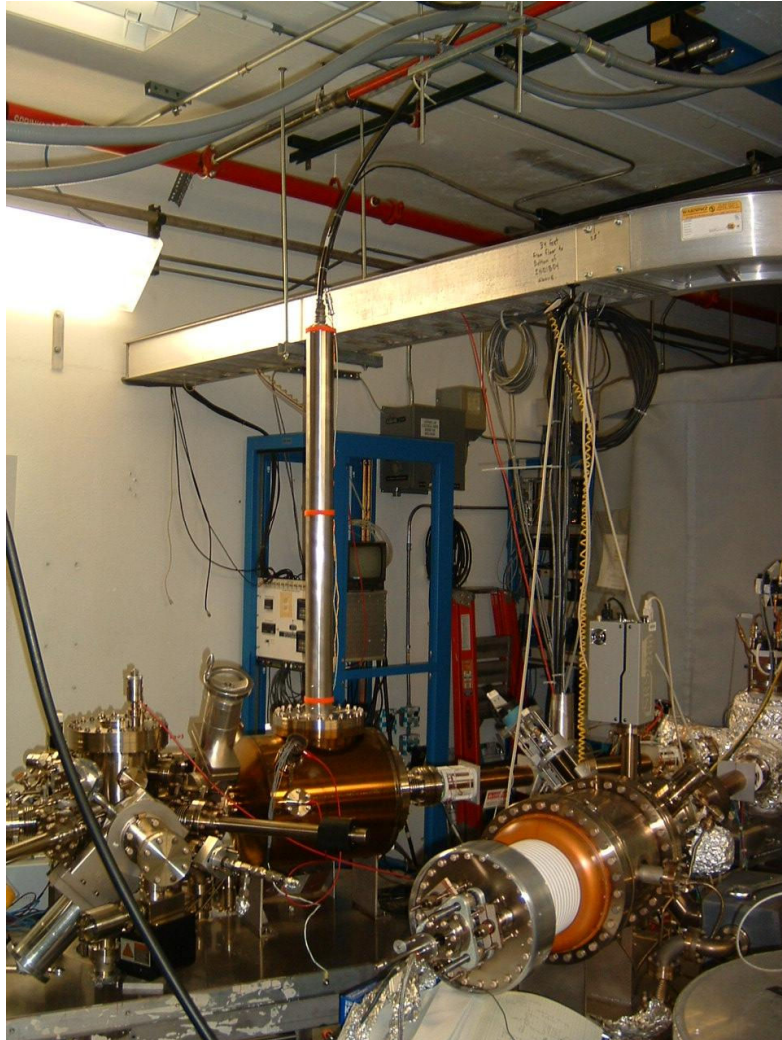
# Inverted Gun assembly







# CEBAF Gun operation



- Inverted Gun installed at CEBAF, operational since July 23, 2009
- Extractor gauge  $2 \times 10^{-12}$  Torr (raw value)
- Happy at 100kV, conditioned to 110kV, briefly went to 125kV
- Opportunity at CEBAF for operation  $> 100$  kV
- Lifetime  $\sim 70$  C at 150  $\mu$ A ave. current
- Aggressive commissioning of 2<sup>nd</sup> InvGun at Test Cave. Under vacuum - with Nb electrode. Ready for beam....



# Lessons Learned

- We learned at CEBAF that it is extremely important to manage ALL of the extracted beam
  - **Anodized edge: beam from outside 5 mm active area can hit beampipe walls, degrade vacuum, reduce operating lifetime**
- ILC/CLIC requires large laser beam to reduce current density and overcome space and surface charge problems
- Need a cathode/anode design that ensures uniform emittance across beam profile. A beam that can be easily managed/transported, with \*ZERO\* beam loss.

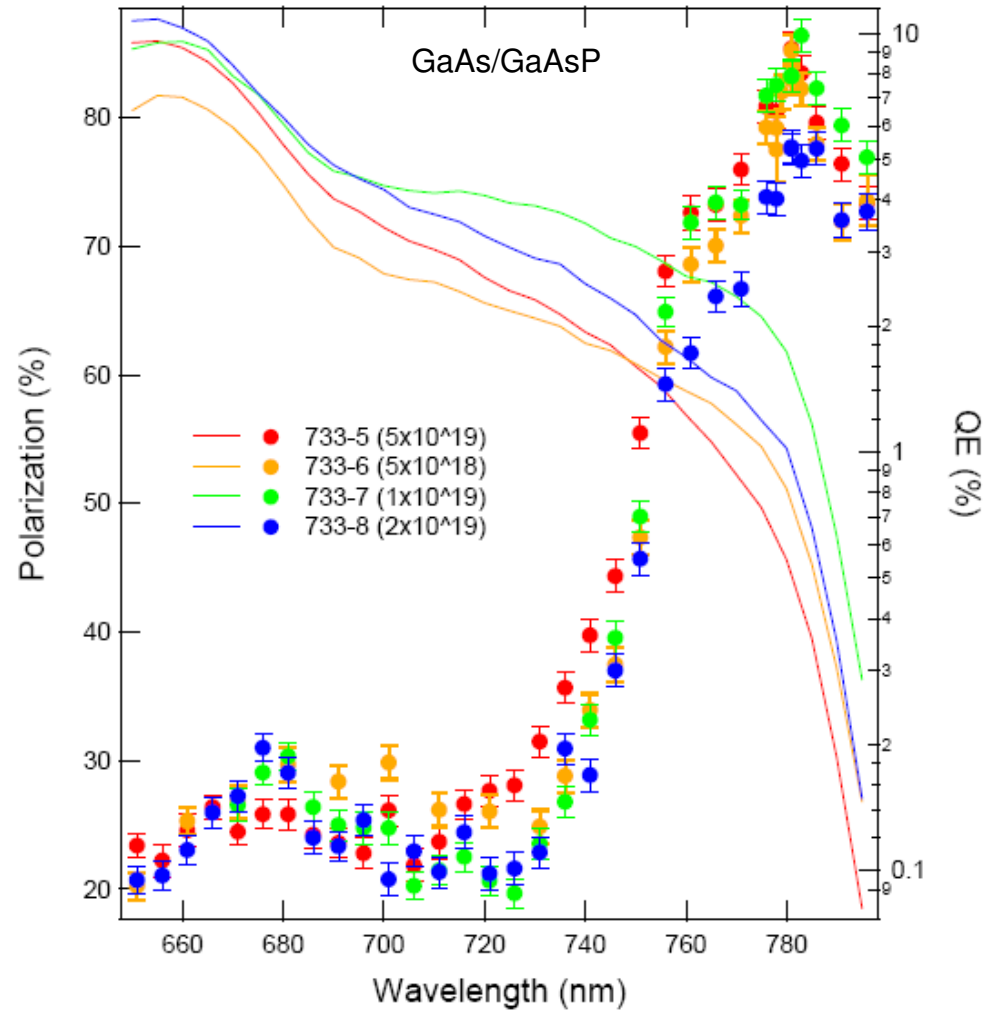


# Photocathode R&D

- Doping Profile Optimization:
  - Measure QE/polarization/surface charge limit as a function of doping level on the surface (5e18, 1e19, 2e19, and 5e19):
  - 5e18 has lower QE but QE of other cases are similar
  - Polarization does not strongly depend on the doping level on the surface.
  - Measure surface charge limit still pending



# Doping Profile Optimization

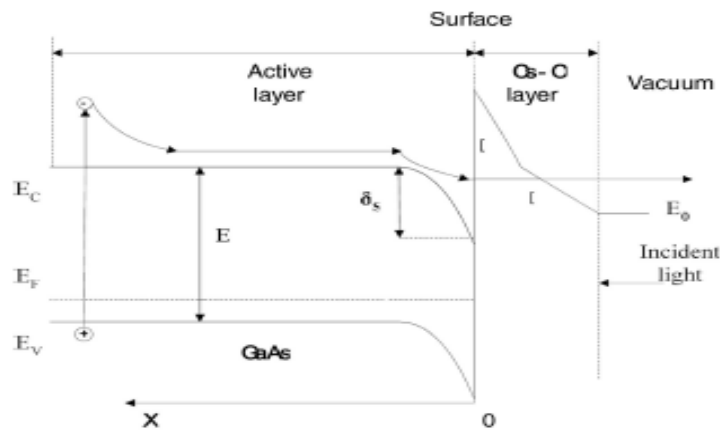




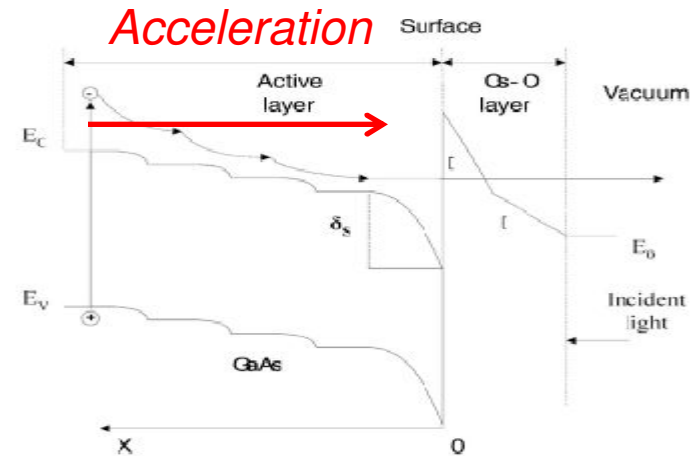
# Internal Bias Effect and DBR

- Measurement of the internal bias effect on QE, polarization, and surface charge limit (wafers are delivered: single layer gradient doped AlGaAs)

Constant doping



Gradient doping



- Distributed Bragg Reflector (DBR) development (SBIR pending)